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(Revision 2)

Electrical conductivity of synthetic mullite single crystals

Mohammed Malki^{1,2*}, Jürgen Schreuer³ and Hartmut Schneider^{4,5}

¹ CEMHTI, Conditions Extrêmes et Matériaux: Haute Température et Irradiation, CNRS UPR
3079, 1D avenue de la Recherche Scientifique, 45071 Orléans cedex 2, France.

² Ecole Polytechnique de l'Université d'Orléans, 45072 Orléans, France.

³ Institut für Geologie, Mineralogie und Geophysik, Ruhr-Universität Bochum,
Universitätsstrasse 150, 44801 Bochum, Germany.

⁴ Institut für Kristallographie, Universität zu Köln, Greinstrasse 6, 50939 Köln, Germany

⁵ Fachbereich Geowissenschaften, Universität Bremen, Klagenfurter Strasse, 28334 Bremen,
Germany

*Corresponding author:

E-mail: mohammed.malki@univ-orleans.fr

Tel.: +33 2 38 25 76 83

Fax: +33 2 38 63 81 03

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ABSTRACT

The electrical conductivity of 2/1-mullite (approximate composition $2\text{Al}_2\text{O}_3 \cdot \text{SiO}_2$) was measured using plane parallel, polished plates cut perpendicular to [100], [010] and [001] from a large single crystal grown by the Czochralski method. Impedance spectra were recorded in the 1 Hz to 1 MHz frequency range at temperatures from 550 °C to 1400 °C in air. The conductivity versus temperature curves display changes of their slope between 850 °C and 950 °C depending on the crystallographical direction. The low temperature region ($T < 850$ °C) of conductivity is characterized by low electrical conductivities ($\sigma_{\text{av}} \approx 5.4 \cdot 10^{-9} \Omega^{-1} \text{cm}^{-1}$, average conductivity at 550°C) with $\sigma_{[010]} > \sigma_{[100]} > \sigma_{[001]}$ and low activation energies (≈ 0.66 eV, average value). In the high temperature region ($T > 950$ °C) the electrical conductivity is significantly higher ($\sigma_{\text{av}} \approx 1.1 \cdot 10^{-5} \Omega^{-1} \text{cm}^{-1}$, average conductivity at 1400 °C) with $\sigma_{[001]} > \sigma_{[100]} \approx \sigma_{[010]}$, and with higher activation energies (≈ 1.6 eV). While the conductivity in the low temperature region essentially is electronic, ion conductivity dominates the conductivity in the high temperature region. We believe that the ionic conductivity is essentially due to hopping of oxygen atoms from structural sites linking the tetrahedral double chains in mullite towards adjacent oxygen vacancies especially in c-axis direction. These oxygen hoppings are associated with complex structural re-arrangements, which control and slow down the velocity of the processes. Thus the electrical conductivity of mullite at high temperature is much lower than e.g. that of Y-doped zirconia, but is significantly higher than that of α -alumina.

Keywords: mullite, single crystals, electrical conductivity, high temperature

58

INTRODUCTION

59 In spite of the fact that mullite occurs only very seldomly in natural rocks it is
60 certainly one of the most widely studied materials in oxide ceramics. This is due to its
61 outstanding properties, especially at high temperatures. Among these properties are the high
62 thermal and chemical stability and the excellent thermo-shock and creep behavior which
63 make mullite a promising candidate for many high temperature applications (see e.g.
64 Schneider and Komarneni, 2005, and the references therein).

65 The crystal structure of mullite can best be described by means of the structurally
66 closely related but more simple sillimanite. The key features of the crystal structure of
67 sillimanite (Figure 1) are edge-sharing octahedral AlO_6 chains running parallel to the **c**-axis
68 (Fischer and Schneider, 2005). The octahedral chains are linked by double chains of corner-
69 sharing MO_4 tetrahedra (also parallel **c**), with an ordered distribution of the tetrahedral cations
70 Al^{3+} and Si^{4+} . Perpendicular to the **c**-axis the situation is different, with a sequence of AlO_6
71 octahedra and AlO_4 and SiO_4 tetrahedra occurring parallel to the **a**- and **b**-axis (Figure 1). The
72 average structure of mullite can be derived from the one of sillimanite by the coupled
73 substitution $\text{Si}^{4+}_{\text{tet}}$ by $\text{Al}^{3+}_{\text{tet}}$ (tet = tetrahedral) and simultaneous Al^{3+} and Si^{4+} disordering over
74 the tetrahedral sites. The excess negative charge in mullite produced by the substitution of
75 Si^{4+} by Al^{3+} is compensated by the formation of oxygen vacancies (see e.g. Fischer and
76 Schneider, 2005). It involves removal of oxygens bridging two adjacent tetrahedra in the
77 sillimanite structure (O(C) oxygen atoms), with the number of vacancies corresponding to the
78 *x*-value of the general formula of the mullite-type alumino silicates $\text{Al}_{4+2x}\text{Si}_{2-2x}\text{O}_{10-x}$. The
79 formation of vacancies causes associated tetrahedral sites TS to be displaced to positions
80 designated as TS*, so that the formerly bridging O(C) oxygen atoms become threefold
81 coordinated and form T_3O groups (the so-called tetrahedral triclusters, TS*, according to
82 literature the TS position is favorably occupied by Al, see Figure 1).

83 A few preliminary studies exist on the electrical conductivity of mullite at high
84 temperatures. Rommerskirchen et al. (1994), on the basis of electromagnetic fields (EMF)
85 measurements on mullite ceramics provided data for an extremely high ionic conductivity of
86 mullite being even superior to that of CaO-stabilized ZrO₂ solid electrolytes at temperatures
87 between 1400°C and 1600°C. Chaudhuri et al. (1999) carried out DC (direct current)
88 measurements to determine the electrical resistivity of undoped and transition metal-doped
89 mullite ceramics at 1400°C. Chaudhuri and coworkers found a much lower electrical
90 conductivity lying in between those of α -alumina and CaO-doped zirconia. Results of
91 Faradaic current studies published by Mata-Osoro et al. (2012) at voltages up to 1000 V on
92 mullite single crystals, ceramics and cermets showed small but measurable currents even at
93 room temperature.

94 The determination of the nature of charge carriers in highly resistive materials is a
95 challenge in general. For mullite, it has been suggested that below about 1000 °C, n-type
96 electronic conduction might be expected to dominate (Buchanan, 2004). Using *ab initio*
97 calculations, Aryal et al. (2012) showed that the 2/1-mullite single crystal is a large band gap
98 insulator with a direct gap at the Brillouin zone center of about 4 eV. Analyzing the
99 temperature dependence of the mullite resistivity up to 1400 °C, Chaudhuri et al. (1999)
100 stated that mullite behaves like a non-metallic electrical conductor because its conductivity
101 rises faster at low temperature but slows down at high temperature. Finally, Rommerskirchen
102 et al. (1994) claimed that the mullite conductivity is predominantly ionic in the temperature
103 range 1400 °C - 1600 °C.

104 As far as we know this is the first study performed on the electrical conductivity of
105 mullite single crystals at high temperatures (up to 1400 °C) and also the first time that
106 electrical conductivity of mullite is measured using impedance spectroscopy. The analysis of
107 frequency dependence using impedance spectroscopy provides information about the dc-
108 conductivity and can also give information on the nature of charge carriers in the samples.

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EXPERIMENTAL

111

112 **Sample preparation**

113 Mullite single crystals of about 2/1-composition ($2\text{Al}_2\text{O}_3 \cdot \text{SiO}_2$) were grown by P.
114 Reiche (Institute of Crystal Growth, IKZ Berlin, Germany). The starting materials were
115 highly pure Al_2O_3 (77.3 wt.%) and SiO_2 (22.7 wt.%) powders which were homogeneously
116 mixed and subsequently melted. Colorless single crystals of high optical quality with
117 dimensions up to 80 mm in length and 20 mm in diameter were obtained employing the
118 Czochralski method (for details see Guse and Mateika, 1974). According to infrared
119 spectroscopic analysis the mullite single crystal is unhydrous (Rüscher et al., 2002). Plane
120 parallel single crystal discs being about 1 mm thick and with about 1 cm^2 surface were cut
121 perpendicular to [100], [010] and [001] from one single crystal, and were subsequently
122 polished.

123 **Electrical conductivity**

124 Impedance spectra were recorded on the samples using a Solartorn SI 1260
125 spectrometer in the frequency range 1 Hz to 1 MHz and in the temperature range 550 °C -
126 1400 °C under air. The electrodes were platinum foils held in contact with the surface sample
127 by a weak mechanical pressure controlled by a spring system and transmitted to the sample
128 using an alumina rod. The sample was placed in the central zone of a vertical tubular furnace
129 where the temperature is uniform. The temperature of the sample was measured using a Pt/Pt-
130 10%Rh thermocouple located near the sample with an uncertainty of $\pm 20 \text{ °C}$

131 Electrical conductivity data of oxides at high temperatures ($T > 1000^\circ\text{C}$) are rather
132 scarce and generally inaccurate. For example, for α -alumina, the magnitude of conductivity
133 determined by different authors varies by up to 4 orders of magnitude (Will, 1992). The
134 difference between the results may be due to impurities and/or to different experimental

135 conditions and procedures. The crucial point when measuring the conductivity is the choice of
136 the electrode metal and configuration. At low temperature ($T < 800^{\circ}\text{C}$), electrodes obtained by
137 sputtering or painting the surface of the sample using Pt, Au or Ag metals generally give good
138 and accurate results. Unfortunately, this method is not applicable at higher temperatures
139 because of the disconnection of metal from the surface sample especially for single crystals
140 where the surface is generally polished. Öijerholm et al (2006) studied the influence of
141 different electrode configurations on the electrical conductivity of α -alumina ceramics and
142 single crystals versus temperature. They concluded that above 700°C , the spring-loaded Pt
143 foil electrodes give accurate results and can be used for their simplicity. However, below 700
144 $^{\circ}\text{C}$ the surface conduction can have a significant influence on the measured conductivity for
145 highly resistive oxides and the use of the so-called guarded electrodes (Macdonald, 1987)
146 may be necessary to prevent such influence.

147 We used spring-loaded and unguarded electrodes in the temperature range 550°C to
148 1400°C . The sample was heated from room temperature up to 1400°C using a rapid heating
149 rate (400°C/h), and then the temperature was held two hours at 1400°C in order to obtain the
150 maximum surface contact by sticking of the electrodes on the sample surface. The data
151 acquisition did not show any increase of the electrical conductivity σ during the plateau at
152 1400°C indicating the good contact electrodes/sample even before reaching 1400°C . After
153 slow cooling (120°C/h) data were recorded by sweeping the frequency from 1 Hz to 1 MHz
154 each 5 minutes. A second heating/cooling cycle was performed on each sample and showed a
155 very good reproducibility of the conductivity results. Only data measured during decreasing
156 the temperature are presented and discussed in this paper. In order to check the contact quality
157 at low temperatures ($T < 700^{\circ}\text{C}$), we used the standard method by sputtering Pt on both faces
158 of the sample after the second cycle at high temperature. The comparison of the results
159 between the two methods (Pt foils and sputtering Pt) show no significant difference

160 suggesting that, on cooling the sample, stable electrode-sample contact is reached after the
161 previous annealing at 1400 °C.

162 RESULTS

163 164 Frequency dependence of the electrical conductivity

165 In order to study the frequency dependence of the electrical conductivity of the single
166 crystals, we used the Cole-Cole (or Nyquist) representation where we plot the opposite of the
167 imaginary part of the complex impedance ($-Z''$) versus its real part (Z'). Two common
168 behaviors against temperature were observed (Figure 2):

169 (1) At high temperatures ($T > 900$ °C), the plot consists of a semicircular arc at high
170 frequencies (left part) and a spike at low frequencies (right part) the length of which increases
171 with temperature. The left side arc is due to the dielectric relaxation process, while the spike
172 is due to the well-known electrode polarization effects and is characteristic of ionic
173 conductors (Grandjean 2006, Macdonald, 1987). The intersection of the curve with the real
174 axis ($Z''=0$) gives the DC-resistance R_{DC} which is related to the static conductivity σ_{DC} by the
175 relationship (Macdonald, 1987):

$$176 \quad \sigma_{DC} = \frac{e}{S} \cdot \frac{1}{R_{DC}} \quad (1)$$

177 where e is the thickness of the sample and S is the electrode surface area.

178 (2) At low temperatures ($T < 900$ °C), the left side arc still exists but the spike is replaced by a
179 flat curve corresponding to $Z''=0$. For these low temperatures and high insulator materials,
180 this flat curve cannot represent the electrode polarization effects. This purely resistive
181 behavior should be a signature of an electronic conductivity. Such behavior has been observed
182 for example in RuO₂-glass composites by Simonnet et al. (2004) who proved the mixed ionic
183 and electronic character of the conductivity in their samples using DC-electrical
184 measurements in the time domain. Unfortunately, this technique was not applicable in the case

185 of our highly resistive samples where the signal versus time was in the order of the magnitude
186 of noise due to the very low value of the DC-current generated in the sample. As we will see
187 in the next section, the value of the activation energy for $T < 900$ °C is also in favor of mixed
188 ionic and electronic conductors.

189 The circular arc (left side) can be fitted using an RC parallel circuit (Macdonald, 1987) which
190 gives $R = 3 \cdot 10^6 \Omega$, $C = 7 \cdot 10^{-12}$ F for $T = 800$ °C and $R = 1.6 \cdot 10^4 \Omega$, $C = 2.2 \cdot 10^{-9}$ F for $T = 1300$
191 °C (Figure 2a and 2b). Using the same fit on the data reported by Chiekh et al (2001) on a
192 single crystal ($ZrO_2 + 9.5\%$ mol Y_2O_3) at 300 °C we found $R = 1.7 \cdot 10^5 \Omega$ and $C = 5.2 \cdot 10^{-11}$ F.
193 The comparison of the resistive part of the two samples shows that the mullite crystal is a
194 better insulator than the yttria doped zirconia one.

195

196 **Temperature dependence of electrical conductivity**

197 Analyzing the frequency dependence of the electrical conductivity allowed us to
198 determine the total DC-electrical conductivity $\sigma(T) = \sigma_{DC}(T)$ as a function of temperature. At
199 high temperatures ($T > 900$ °C), the conductivity $\sigma(T)$ is predominantly ionic and at low
200 temperatures ($T < 900$ °C), there is most probably an electronic contribution to the DC-
201 conductivity. However, due to the highly resistive character of our samples, we were not able
202 to separate each contribution (ionic and electronic) and its evolution with temperature.

203 Figure 3 shows the evolution of the DC-conductivity versus $10^4/T$ for the different
204 orientations of the mullite single crystal sample. Applying the propagation of error formula
205 (Ku, 1966) to equation 1:

$$206 \quad \frac{\Delta\sigma}{\sigma} = \frac{\Delta e}{e} + \frac{\Delta S}{S} + \frac{\Delta R}{R} \quad (2)$$

207 we estimate the error of the conductivity σ to ± 5 % at the highest temperature ($T = 1400$ °C).

208 At lower temperatures, however, the uncertainty of R increases because of the use of

209 unguarded electrodes (Öijerholm et al., 2006). The estimated error bars of the conductivity σ
210 are shown in Figure 3 only on the [001] orientation for some selected temperatures for clarity.
211 The first important observation is that in the investigated temperature interval from 550 °C to
212 1400 °C the conductivity lies between about $10^{-9} \Omega^{-1} \text{cm}^{-1}$ and $10^{-5} \Omega^{-1} \text{cm}^{-1}$. This means that
213 mullite single crystal is an electrical insulator material even at high temperature ($\sigma \approx 1.3 \cdot 10^{-5}$
214 $\Omega^{-1} \text{cm}^{-1}$ at 1400°C). We also notice that the conductivity curve exhibits the same global trend
215 for the three crystallographic directions with a change in the slope between $T \approx 850$ °C and T
216 ≈ 950 °C depending on the crystal orientation. In the low temperature range (LTR) the slope is
217 lower than in the high temperature range (HTR).

218 In order to describe the evolution of the electrical conductivity with temperature T and to
219 compare our results with previous ones, we used the “original” Arrhenius equation,

$$220 \quad \sigma(T) = \sigma_0 \exp\left(-\frac{E_a}{kT}\right) \quad (3)$$

221 where k is the Boltzmann constant, E_a is the activation energy associated with the transport
222 mechanism and σ_0 is a pre-exponential factor. The obtained values of E_a and σ_0 for the three
223 crystallographic orientations are summarized in Table 1. The rather low value of the activation
224 energy (≈ 0.64 eV) observed in the LTR supports the assumption of a mixed ionic and
225 electronic conductivity we already suggested by analyzing the frequency dependence of
226 electrical conductivity, whereas the high value in the HTR is consistent with an ionic
227 conductivity driven by oxygen ions associated to vacancies (see discussion).

228

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DISCUSSION

230 Our experimental results clearly indicate that the electrical conductivity of mullite single
231 crystal is controlled by two processes with different activation energies (Table 1). Below
232 about 800 °C the conductivity is dominated by electronic contributions with the highest
233 conductivity along [010] and with $\sigma_{[010]} > \sigma_{[100]} > \sigma_{[001]}$ ($\sigma_{av} \approx 5.4 \cdot 10^{-9} \Omega^{-1} \text{cm}^{-1}$, average

234 conductivity at 550 °C). Above about 800 °C ionic conductivity becomes more and more
235 important, particularly along the [001] direction, which eventually leads to an anisotropic
236 electrical conductivity characterized by $\sigma([001]) > \sigma([100]) \approx \sigma([010])$. For example, at about
237 1400 °C the observed values are $\sigma_{[001]} = 1.31(7) \cdot 10^{-5} \Omega^{-1} \text{cm}^{-1}$, $\sigma_{[100]} = 1.01(5) \cdot 10^{-5} \Omega^{-1} \text{cm}^{-1}$
238 and $\sigma_{[010]} = 0.98(5) \cdot 10^{-5} \Omega^{-1} \text{cm}^{-1}$ ($\sigma_{\text{av}} \approx 1.1 \cdot 10^{-5} \Omega^{-1} \text{cm}^{-1}$, average conductivity at 1400 °C).
239 The changing anisotropy of the electrical conductivity of mullite in the low and high
240 temperature region can be clearly seen in Figure 4 where typical representation surfaces of the
241 longitudinal electrical conductivity are shown. From the phenomenological point of view
242 electrical conductivity can be considered a second rank tensor $\{\sigma_{ij}\}$ in first approximation.
243 Following this, the longitudinal conductivity $\sigma(\mathbf{u})$ along an arbitrary direction $\mathbf{u} = u_i \mathbf{e}_i$ ($|\mathbf{u}| =$
244 1, \mathbf{e}_i are the axes of the Cartesian reference system, i.e. $\mathbf{e}_1//\mathbf{a}$, $\mathbf{e}_2//\mathbf{b}$ and $\mathbf{e}_3//\mathbf{c}$ in the case of
245 orthorhombic mullite) is given by $\sigma(\mathbf{u}) = u_i u_j \sigma_{ij}$ (Einstein's sum convention applies).

246 Apart from the relatively low onset temperature of about 800 °C, the development of
247 ionic conductivity with temperature fits well to the picture of a glass-like transition derived
248 from anomalies observed in the temperature evolutions of heat capacity (Hildmann and
249 Schneider, 2004), thermal expansion (Schreuer et al., 2006, Schneider et al., 2008), and elastic
250 constants (Schreuer et al. 2006) for example. According to Schneider et al. (2008) the
251 distribution of defects, namely the oxygen vacancies required for charge compensation and
252 the triclusters (cf. Figure 1), is in a frozen-in state at low temperatures. At high temperatures
253 hopping of oxygen atoms, bridging tetrahedral double chains (O(C) oxygen atoms) towards
254 neighboring oxygen vacancies are possible. Gradual activation of this site-exchange processes
255 leads to a glass-like static \leftrightarrow dynamic transition. According to this model, the onset of oxygen
256 ion mobility and the correlated oxygen ion conductivity is associated with the observed
257 discontinuous changes of the slopes of $\sigma(10^4/T)$. Because hopping of oxygen atoms can occur
258 more easily between O(C) atoms and neighboring O(C) vacancies parallel to the \mathbf{c} -axis than
259 perpendicular to it, the anomaly in the σ versus $10^4/T$ curve occurs at lower temperatures (850

260 ± 20 °C) along [001] and at higher temperatures for directions within the (001) plane ($890 \pm$
261 20 °C along [100] and 950 ± 20 °C along [010]). However, the small anisotropy of
262 conductivities parallel and perpendicular to the crystallographic *c*-axis shows that oxygen
263 hoppings have only a limited influence. This agrees well with the observation that oxygen
264 diffusion in mullite displays no significant anisotropy (Fielitz et al. 2001a,b). The broad
265 variation of the glass transformation temperature ranging between about 850 °C derived from
266 electrical conductivity and up to about 1200 °C from calorimetric experiments cannot be
267 explained so far. It is not clear whether the different frequency regimes, and time and lengths
268 scales of the experiments can account for the large spread.

269 The little impact of oxygen hoppings along to the crystallographic *c*-axis on the
270 electrical conductivity can be explained by the complexity of site-exchange processes. The
271 entering of an oxygen into a neighboring vacancy eliminates this vacancy by forming a new
272 tetrahedral T-O(C)-T (T = Al³⁺, Si⁴⁺) bridge. This goes along with a migration of the TS*
273 tricluster cations adjacent to the former O(C) oxygen vacancy to newly formed TS sites².
274 Simultaneously a new vacancy at the originally occupied O(C) site is produced (see Schneider
275 et al. 2008, Figure 24). The latter requires a migration of the two tetrahedral TS atoms
276 adjacent to the originally occupied O(C) atoms to the newly formed tetrahedral TS* tricluster
277 sites. These structural rearrangements are much more sluggish than are simple O(C) hoppings
278 and thus control the velocity of the whole process. The complex structural processes
279 associated with these hoppings explain (i) the relative high values of activation energy in the
280 high temperature conductivity region of mullite (≈ 1.6 eV) compared to that of Y₂O₃-doped
281 ZrO₂ single crystal (≈ 0.82 eV) as reported by Filal et al. (1995) (note that in the paper of Filal
282 et al., 1995, the value of activation energy is given as 0.90 eV because the authors considered
283 a modified Arrhenius-type equation), and (ii) why the oxygen ionic conductivity in mullite is
284 much lower than that of effective oxygen ion conductors like CaO- or Y₂O₃-doped ZrO₂ ($\sigma \approx$
285 $10^{-6} \Omega^{-1}\text{cm}^{-1}$ for mullite instead of $\sigma \approx 10^{-1} \Omega^{-1}\text{cm}^{-1}$ for 3%Y₂O₃-doped ZrO₂, both values for

286 1100°C, see Figure 5). Furthermore, the complex structural processes of oxygen mobility
287 make the high oxygen ionic conductivities beyond 1400°C as published by Rommerskirchen
288 et al. (1994) rather unlikely. On the other hand due to the contribution of ionic conductivity
289 the overall conductivity of mullite is higher than it is in high temperature insulators like α -
290 alumina (at 1100 °C $\sigma(\text{mullite}) \approx 10^{-6} \Omega^{-1}\text{cm}^{-1}$ instead of $\sigma(\alpha\text{-alumina}) \approx 10^{-10} \Omega^{-1}\text{cm}^{-1}$, Figure
291 5).

292 The mean electrical conductivity of mullite single crystals in the low temperature
293 region displays a similar temperature-dependent behavior with comparable activation energies
294 as that obtained by Chaudhury et al. (1999) from polycrystalline mullite ceramics, although
295 the latter is significantly higher (Figure 6). The difference between both data sets is explained
296 by the contribution of grain boundary effects to the overall conductivity in the case of
297 ceramics caused by an enrichment of defects and impurities at the grain boundaries. In the
298 high temperature region the difference between single crystal and polycrystalline ceramic data
299 is continuously reduced with temperature and becomes almost zero at about 1400 °C (Figure
300 6). One reason of it may be the number of oxygen vacancies which are required for oxygen
301 ionic conductivity. This number is higher in Al-rich 2/1-mullite single crystals ($x = 0.4$,
302 corresponding to 2 oxygen vacancies per 5 unit cells) than in 3/2-mullite polycrystalline
303 ceramics ($x = 0.25$, corresponding to 1 oxygen vacancy per 4 unit cells). The influence of
304 grain boundaries probably is less important, since the free paths of ions and electrons between
305 collisions is less than about 150 Å (see Kingery et al. 1975).

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FIGURE CAPTIONS

364 **Figure 1.** Crystal structure of mullite in comparison to that of sillimanite in projections
365 parallel [001] (above) and parallel [100] (below). The structure plots of mullite give a
366 schematic and simplified view of the oxygen vacancies and the tetrahedral triclusters (see the
367 text).

368 **Figure 2.** Cole-Cole (or Nyquist) plots for the crystal [001] at two temperatures (a) $T = 800$
369 °C and (b) $T = 1300$ °C. Z' and Z'' represent the real and the imaginary parts of the complex
370 impedance, respectively. Scatters represent the experimental points and solid lines the fit of
371 the circular arc (left side) using an RC parallel circuit (see text).

372 **Figure 3.** Arrhenius plot of the DC conductivity for the three mullite single crystals. Solid
373 lines represent the fit of the experimental points using equation 2 (see text).

374 **Figure 4.** Representation surfaces of longitudinal electrical conductivity of mullite single
375 crystal at 550 °C (left) and 1400 °C (right). Units of axes are $10^{-9}\Omega^{-1}\text{cm}^{-1}$ and $10^{-6}\Omega^{-1}\text{cm}^{-1}$,
376 respectively.

377 **Figure 5.** Comparison of the electrical conductivity of the single crystals: mullite [001] (this
378 work), pure alumina [001] (Will et al., 1992) and 3% Y_2O_3 -doped ZrO_2 (Filal et al., 1995).

379 **Figure 6.** Comparison between the mean electrical conductivity of the three orientations of
380 our mullite single crystals and the conductivity of the mullite ceramic reported by Chaudhury
381 et al. (1999).

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Table 1

	[001] LTR	[001] HTR	[100] LTR	[100] HTR	[010] LTR	[010] HTR
E_a (eV)	0.68 ± 0.12	1.64 ± 0.04	0.64 ± 0.12	1.64 ± 0.04	0.64 ± 0.17	1.57 ± 0.06
$\log(\sigma_0)$	-4.36 ± 0.26	0.01 ± 0.05	-4.45 ± 0.26	-0.13 ± 0.05	-4.25 ± 0.26	-0.33 ± 0.05

Table 1. Activation energy (E_a) and pre-exponential factor ($\log(\sigma_0)$) values for the electrical conductivity along to [001], [100] and [010] of mullite in low temperature region (LTR) and in high temperature one (HTR).

Figure 1

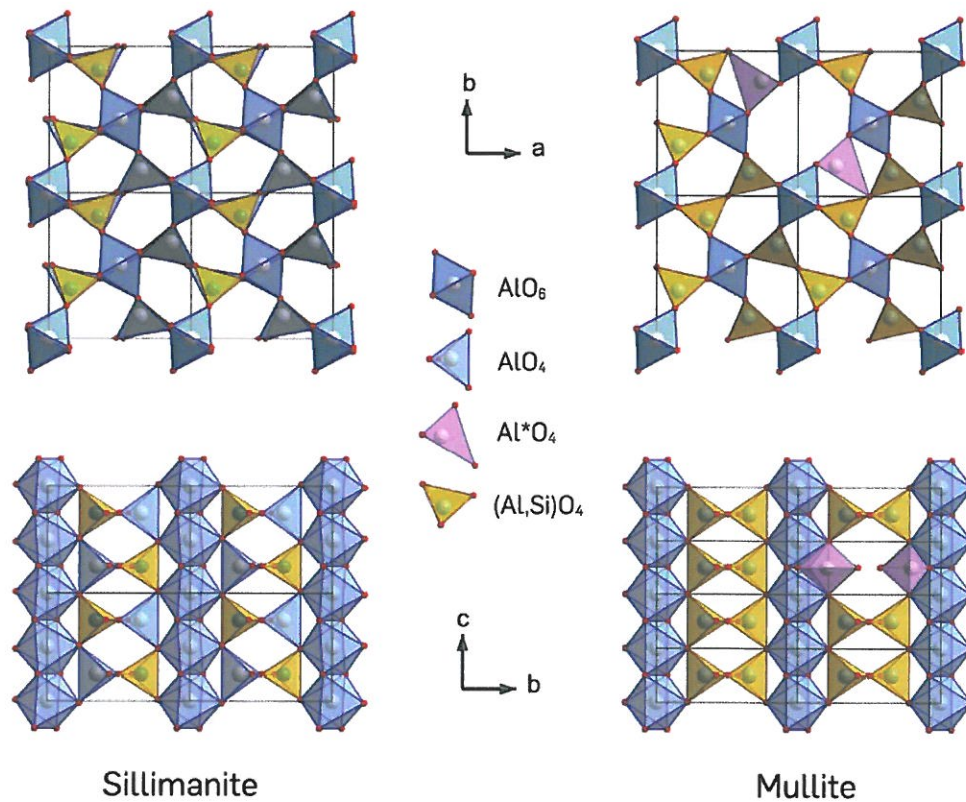


Figure 1. Crystal structure of mullite in comparison to that of sillimanite in projections parallel [001] (above) and parallel [100] (below). The structure plots of mullite give a schematic and simplified view of the oxygen vacancies and the tetrahedral triclusters (see the text).

Figure 2

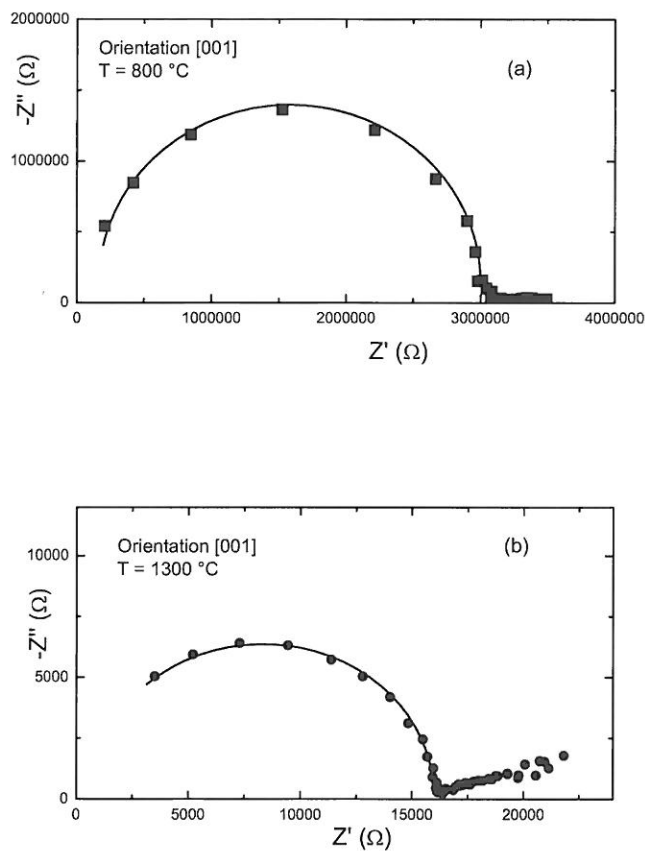


Figure 2. Cole-Cole (or Nyquist) plots for the crystal [001] at two temperatures (a) $T=800\text{ }^{\circ}\text{C}$ and (b) $T = 1300\text{ }^{\circ}\text{C}$. Z' and Z'' represent the real and the imaginary parts of the complex impedance respectively. Scatters represent the experimental points and solid lines the fit of the circular arc (left side) using an RC parallel circuit (see text).

Figure 3

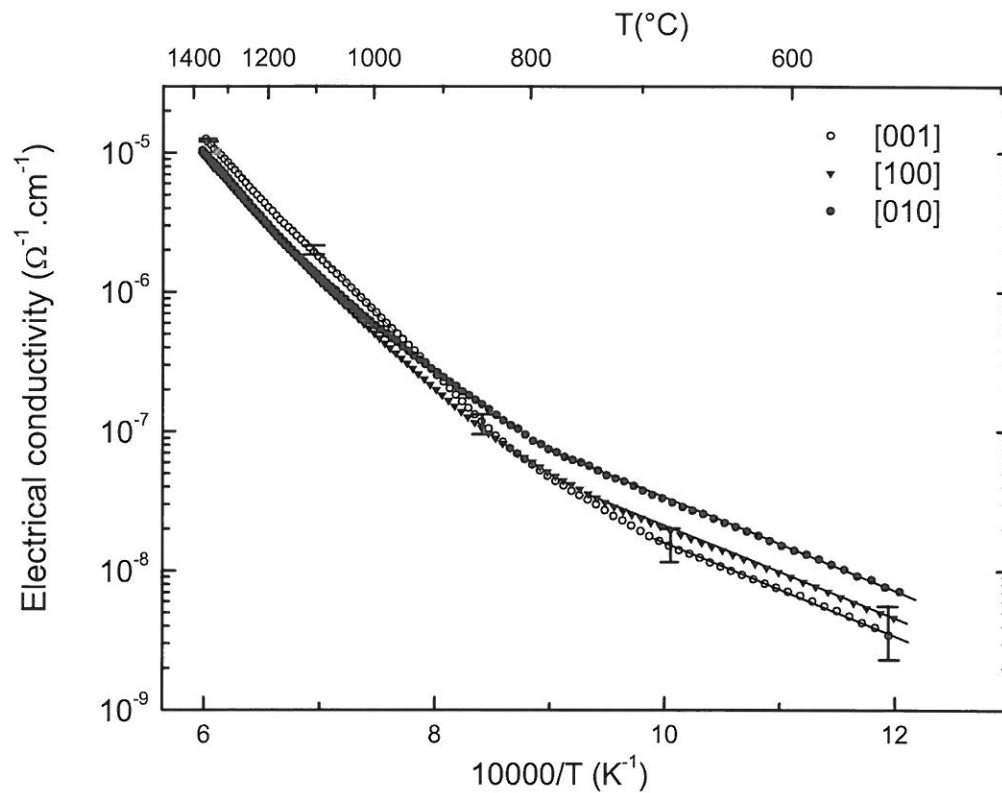


Figure 3. Arrhenius plot of the dc conductivity for the three mullite single crystals. Solid lines represent the fit of the experimental points using equation 3 (see text).

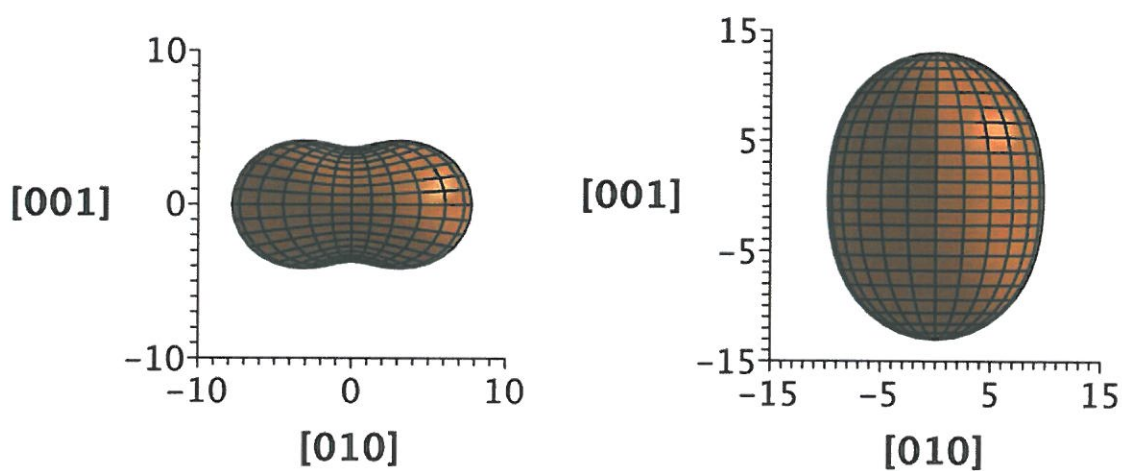


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Figure 5

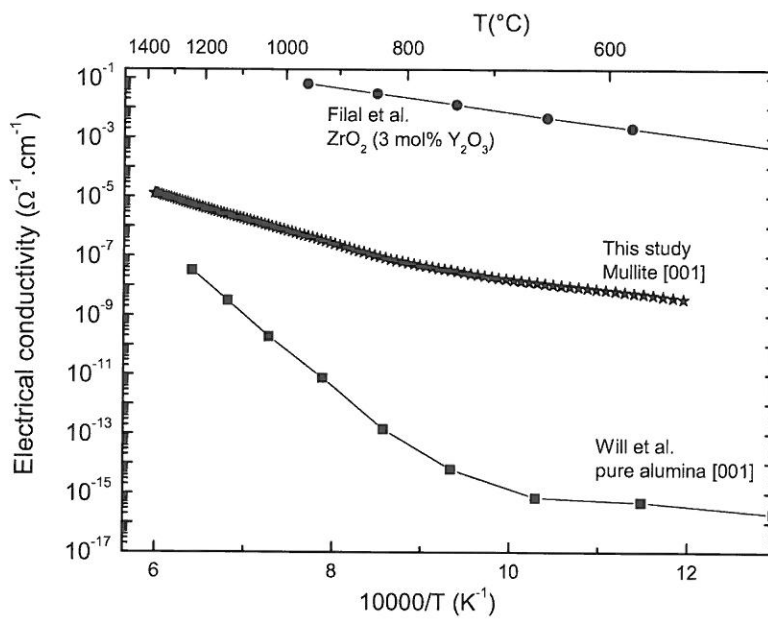


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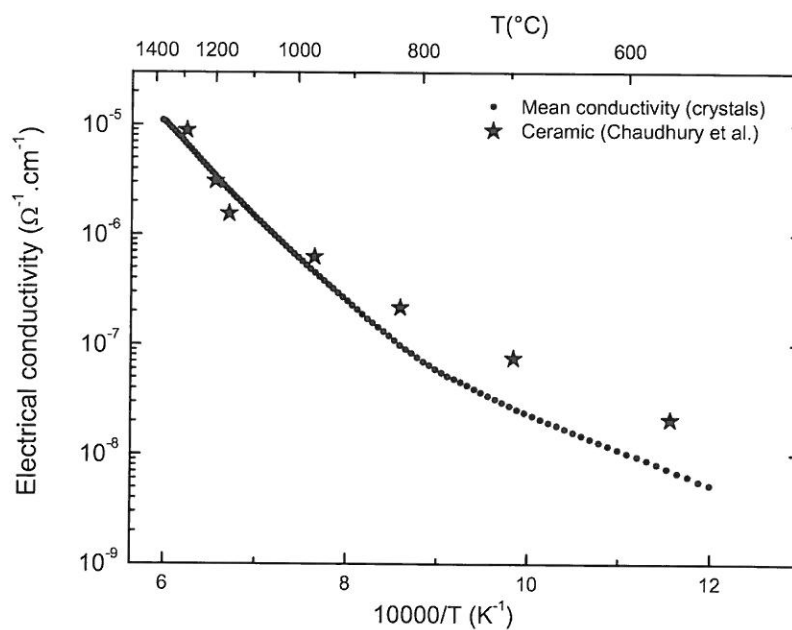


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